
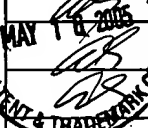
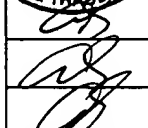
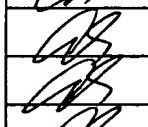
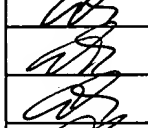
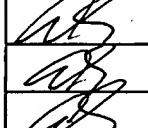
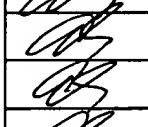
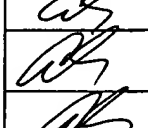
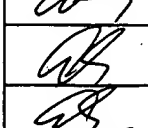
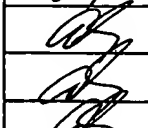
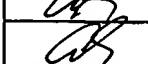
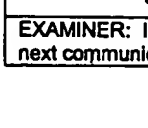

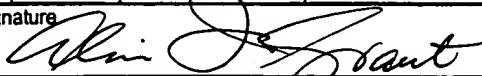


Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05542-451001	Application No. 09/847,867
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Boguslaw Swedek et al.	
		Filing Date May 2, 2001	Group Art Unit 3723

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Examiner Signature

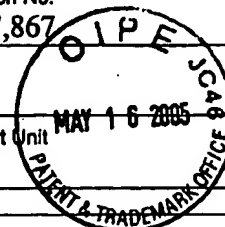


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Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
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	ANN	
	AOO	

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Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 1.98(b))		Applicant Boguslaw Swedek et al.	
		Filing Date May 2, 2001	Group Art Unit 3723

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	AI						
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	AK						

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	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

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	AR	
	AS	
	AT	

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